

# MICRONICS JAPAN CO., LTD.

President & CEO  
YOSHIEI HASEGAWA

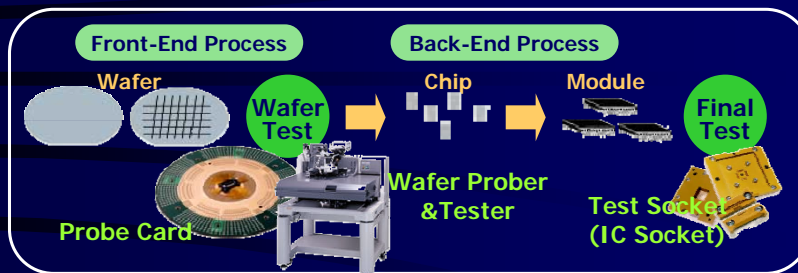
Feb. 26, 2007



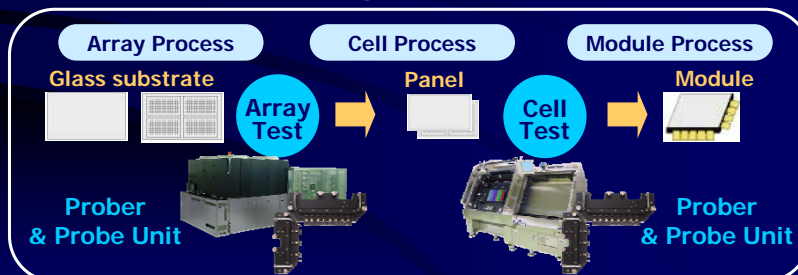
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## Business Field

SEMICON  
DUCTOR

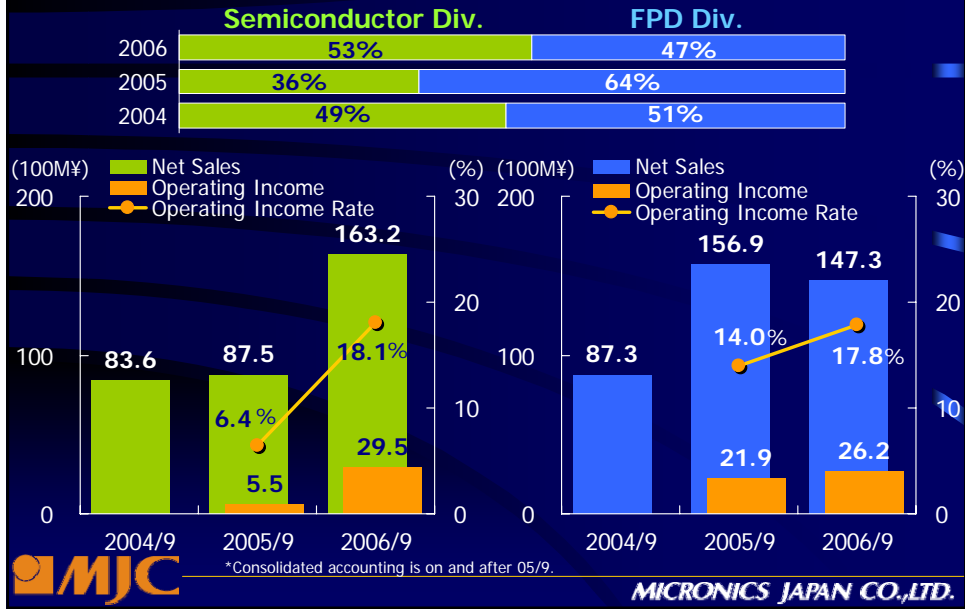


FPD(LCD)

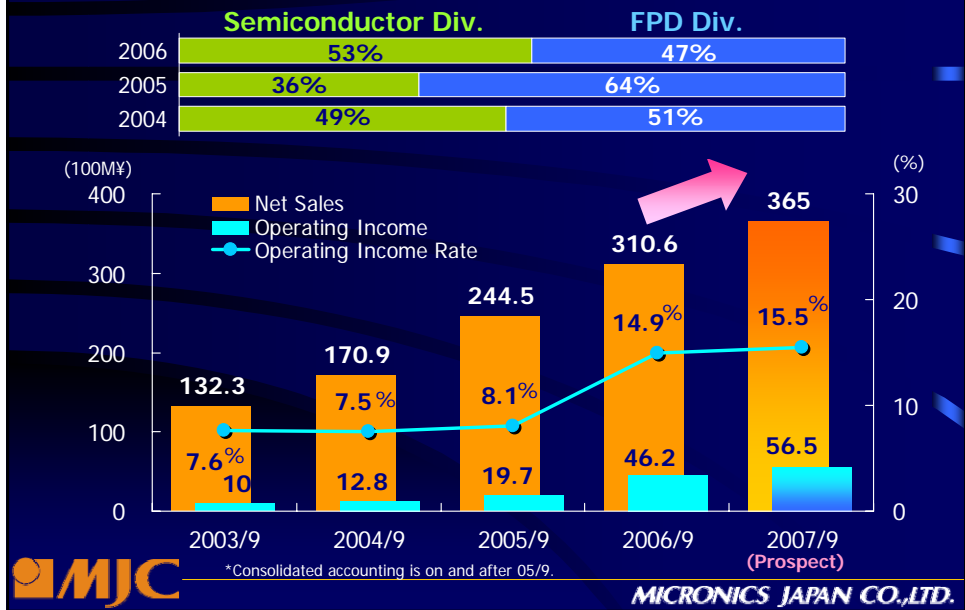


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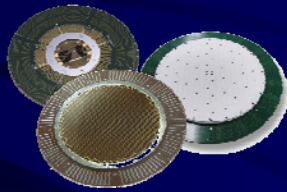
# Business Performance Transition



# Business Performance Transition

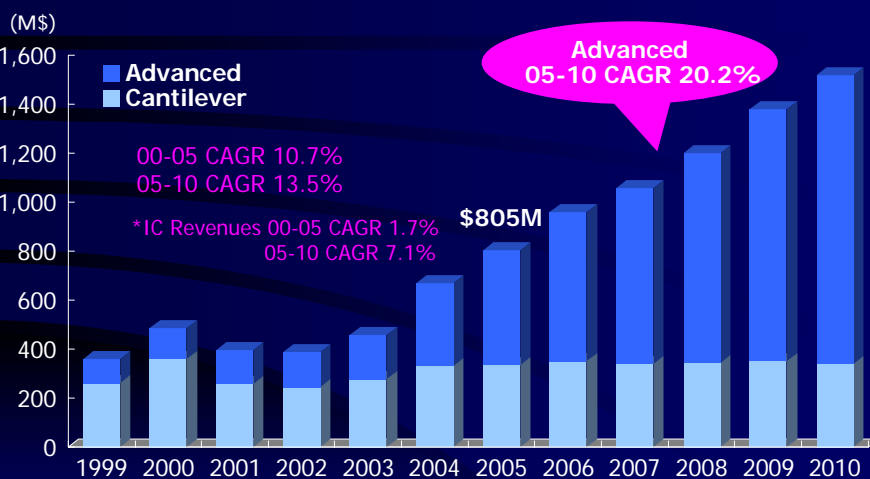


# Semiconductor DIV.

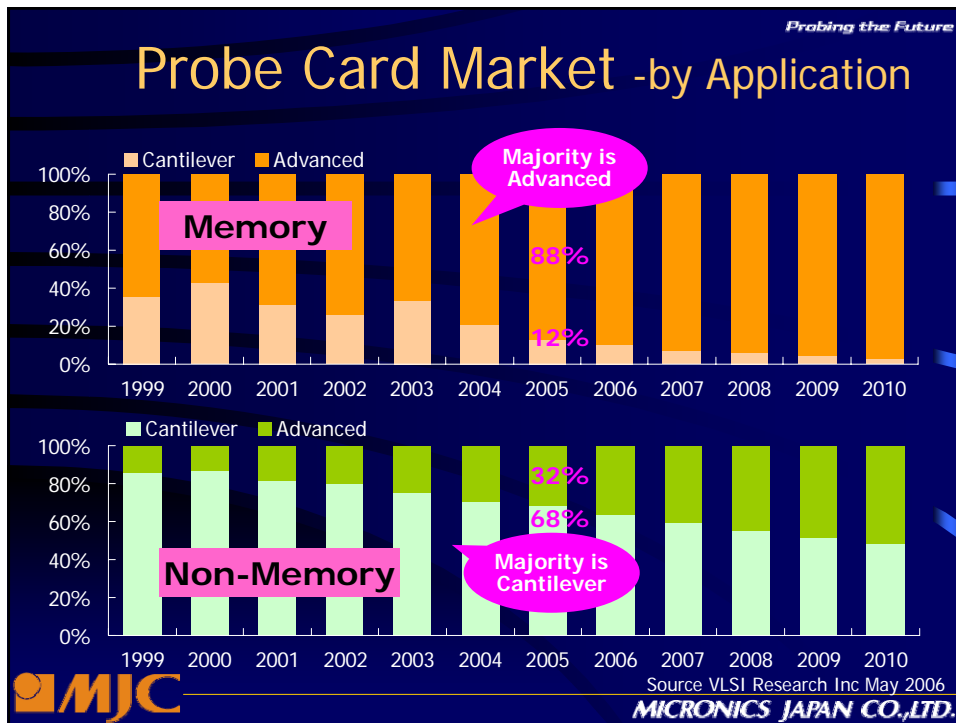


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# Probe Card Market -by Technology



Source VLSI Research Inc May 2006  
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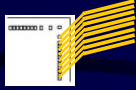


*Probing the Future*

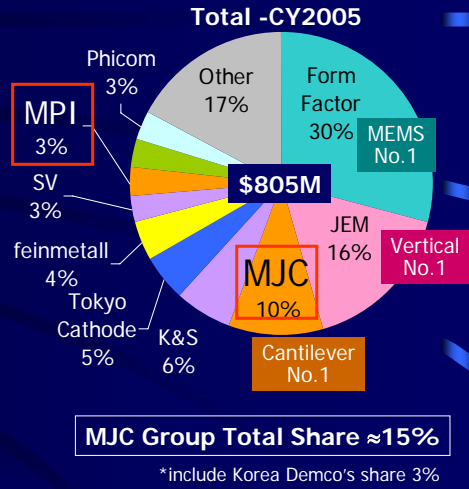
## Why Advanced Probe Card

- ✦ **Improve Test efficiency**  
 Most suitable multi-Die test  
 ex. DRAM Cantilever 64DUT, Vertical 128DUT,  
 MEMS 256DUT/384DUT
- ✦ **Response to miniaturized structure Device**  
 Fine Pitch, small PAD, etc...
- ✦ **Fit the Known Good Die (KGD) Test**  
 At-speed Test, Wafer Level Burn IN (WLBI) Test

**MJC** **MICRONICS JAPAN CO., LTD.**

# Probe Card Types & Vendors

	Shape and features	Price	Market	Delivery
Canti	Cantilever-type 	Low ↑ ↓ High	Vendor More ↑ ↓ Less	Short ↑ ↓ Relatively Long
	Vertical-type 			
Advanced Lithography-type (MEMS, Membrane) 				



Source VLSI Research Inc May 2006

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# What Probe Card is needed?

⊙ Current market standard    — No demand in current market

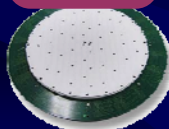
	Memory			Logic		LCD driver	
	DRAM	Flash	Other	Peripheral	Area array (Existing)	Existing	Fine pitch High-FQ Multi-Die
Canti	△	△	○	⊙	△	⊙	△
Vertical	○ (WLBI ⊙)	○ (BIST ⊙)	○	△	⊙	×	
Litho	⊙	⊙	○	—	○	△	⊙

U-Probe



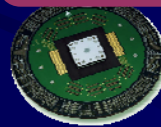
1 touchdown is world first

SP-Probe



1 touchdown for BIST

Vertical-Probe



fine pitch of 70um

LCD-S



MJC makes a monopoly

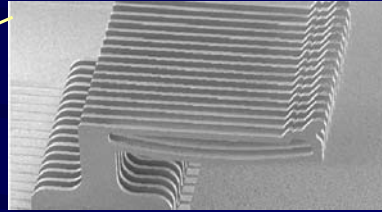
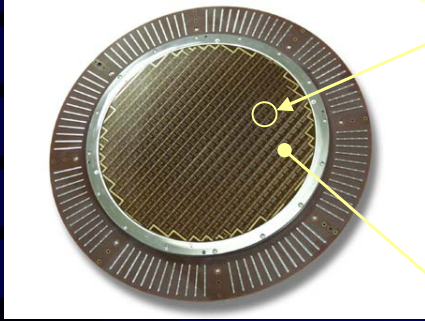


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# MJC's MEMS Probe Card

"U-Probe"

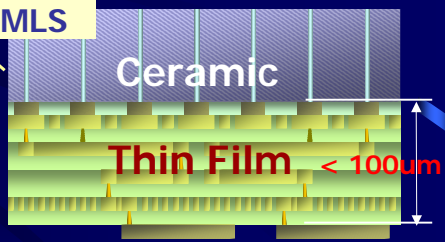
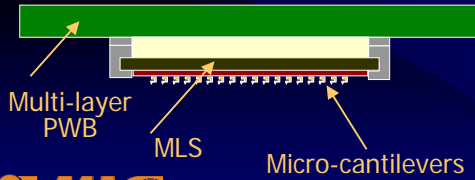
Micro-cantilevers



MLS

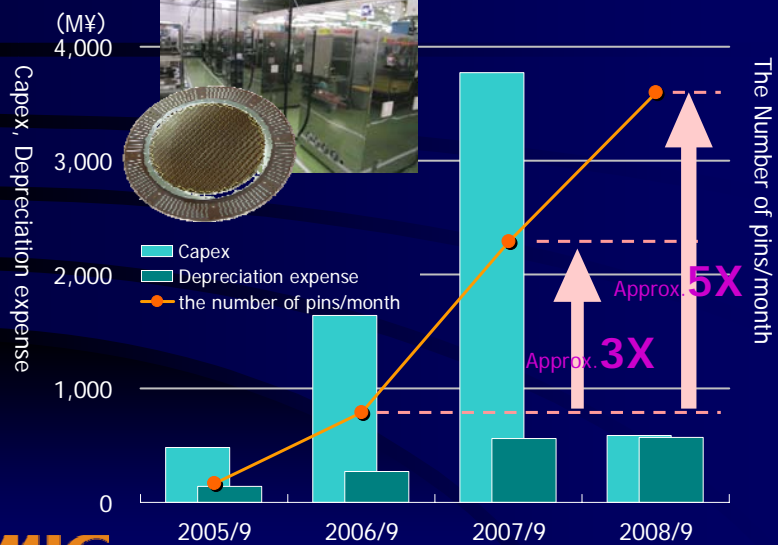
Ceramic

Thin Film < 100µm



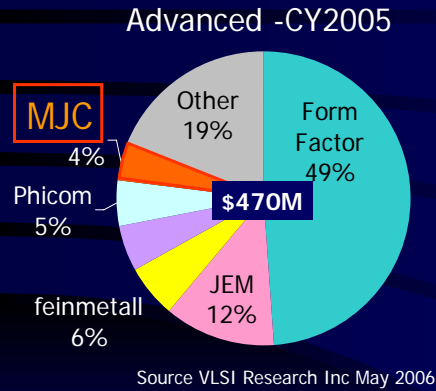
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# U-Probe Capex Planning



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# Market Share Target



Our share of Advanced Probe Card in CY 2006 is expected to reach 9%.

**Target in CY 2008 is Share 25% or more.**

\* Share 20% or more of all Probe card.



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# Tester Business

## BIST Tester

was developed for NAND Flash , in CY2006.

Sold for 20M¥ in CY2006.



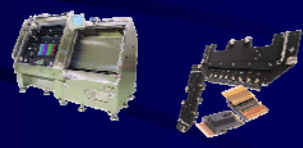
In the near future...

WLBI Tester for DRAM



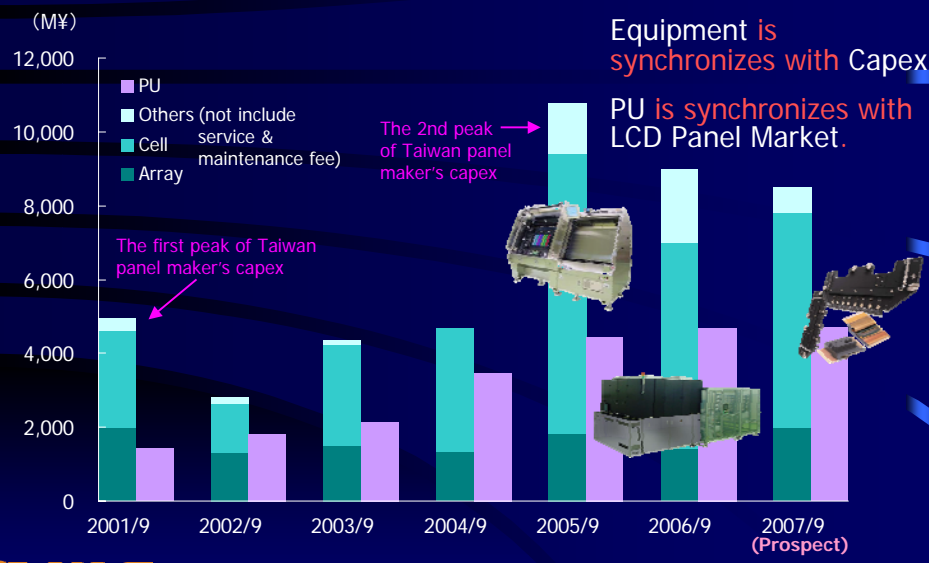
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# FPD DIV.



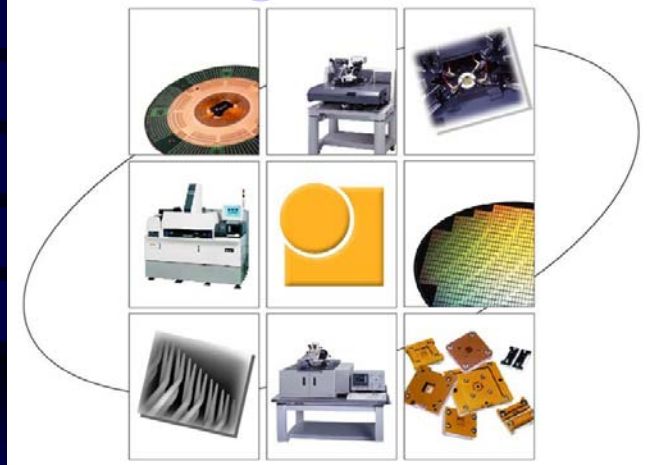
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# LCD Test Equipment



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# Probing the Future



## Notice

Contents in this presentation material such as the product situation in the market are described based on information we can collect at present. Also, our strategy and goals are based on our present situation. Thus, please keep in mind that actual market situation and our future situation may be quite different from the description and information in this presentation material.



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